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THS7530-Q1 SLOS932 - DECEMBER 2015

# THS7530-Q1 High-Speed, Fully Differential, Continuously Variable Gain Amplifier

#### Features 1

- Qualified for Automotive Applications
- AEC-Q100 Qualified With the Following Results:
  - Device Temperature Grade 1: –40°C to +125°C Ambient Operating Temperature Range
  - Device HBM Classification Level 2
  - Device CDM Classification Level C6
- Low Noise:  $V_n = 1.1 \text{ nV}/\sqrt{\text{Hz}}$ , Noise Figure = 9 dB
- Low Distortion:
  - HD<sub>2</sub> = -65 dBc, HD<sub>3</sub> = -61 dBc at 32 MHz
- IMD<sub>3</sub> = -62 dBc, OIP<sub>3</sub> = 21 dBm at 70 MHz
- 300-MHz Bandwidth
- Continuously Variable Gain Range: 11.6 dB to 46.5 dB
- Gain Slope: 38.8 dB/V
- Fully Differential Input and Output
- Output Common-Mode Voltage Control
- **Output Voltage Limiting**

#### Applications 2

- Time Gain Amplifiers in Ultra Sound, Sonar, and Radar
- Automatic Gain Control in Communication and Video
- System Gain Calibration in Communications

Variable Gain in Instrumentation

# 3 Description

Tools &

Software

The THS7530-Q1 device is fabricated using Texas Instruments' state-of-the-art BiCom Ш SiGe complementary bipolar process. The THS7530-Q1 device is a DC-coupled, wide bandwidth amplifier with voltage-controlled gain. The amplifier has highimpedance differential inputs and low-impedance differential outputs with high-bandwidth gain control, output common-mode control, and output voltage clamping.

Signal-channel performance is exceptional with 300-MHz bandwidth, and third harmonic distortion of –61 dBc at 32 MHz with 1-V<sub>PP</sub> output into 400 Ω.

Gain control is linear in dB with 0 V to 0.9 V varying the gain from 11.6 dB to 46.5 dB with 38.8-dB/V gain slope.

Output voltage limiting is provided to limit the output voltage swing and to prevent saturating following stages.

The device is characterized for operation over the automotive temperature range, -40°C to +125°C.

### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)			
THS7530-Q1	HTSSOP (14)	5.00 mm × 4.40 mm			

(1) For all available packages, see the orderable addendum at the end of the data sheet.

# Typical Application Circuit



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# 4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
December 2015	*	Initial release.



# 5 Pin Configuration and Functions



#### **Pin Functions**

P	PIN		DESCRIPTION
NAME	NO.	I/O	DESCRIPTION
NC	1		No internal connection
NC.	2		No internal connection
PD	7	_	Power down, $\overline{PD}$ = logic low puts the device into low power mode; $\overline{PD}$ = logic high or open for normal operation
V <sub>CL-</sub>	13	I	Output negative clamp voltage input
V <sub>CL+</sub>	14	I	Output positive clamp voltage input
V <sub>G-</sub>	6	I	Gain setting negative input
V <sub>G+</sub>	5	I	Gain setting positive input
V <sub>IN-</sub>	4	I	Inverting amplifier input
V <sub>IN+</sub>	3	I	Noninverting amplifier input
V <sub>OCM</sub>	12	I	Output common-mode voltage input
V <sub>OUT-</sub>	11	0	Inverted amplifier output
V <sub>OUT+</sub>	10	0	Noninverted amplifier output
V <sub>S-</sub>	8	Ι	Negative amplifier power-supply input
V <sub>S+</sub>	9	I	Positive amplifier power-supply input

# 6 Specifications

### 6.1 Absolute Maximum Ratings

Over operating free-air temperature range, unless otherwise noted.<sup>(1)</sup>

		MIN	MAX	UNIT
$V_{S+} - V_{S-}$	Supply voltage		5.5	V
VI	Input voltage		$\pm V_S$	V
lo	Output current		65	mA
V <sub>ID</sub>	Differential input voltage		±4	V
	Continuous power dissipation	See	Thermal Inforn	nation
-	Maximum junction temperature		150	°C
IJ	Maximum junction temperature for long term stability <sup>(2)</sup>		125	°C
T <sub>stg</sub>	Storage temperature	-65	150	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The maximum junction temperature for continuous operation is limited by package constraints. Operation above this temperature may result in reduced reliability and/or lifetime of the device.

### 6.2 ESD Ratings

			VALUE	UNIT
V		Human-body model (HBM), per AEC Q100-002 <sup>(1)</sup>	±2000	N/
V <sub>(ESD)</sub> Electrostatic	SD) Electrostatic discharge	Charged-device model (CDM), per AEC Q100-011	±1000	V

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

# 6.3 Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
$[\mathrm{V}_{\mathrm{S}-} \text{ to } \mathrm{V}_{\mathrm{S}+}]$	Supply voltage		4.5	5	5.5	V
	Input common mode voltage	$[V_{S-} \text{ to } V_{S+}] = 5 \text{ V}$		2.5		V
	Output common mode voltage	$[V_{S-} \text{ to } V_{S+}] = 5 \text{ V}$		2.5		V
T <sub>A</sub>	Operating free-air temperature		-40		125	°C

#### 6.4 Thermal Information

	THERMAL METRIC <sup>(1)</sup>	PWP (HTSSOP)	UNIT
		14 PINS	
$R_{ extsf{ heta}JA}$	Junction-to-ambient thermal resistance	75.3	°C/W
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	35	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	28.9	°C/W
Ψ <sub>JT</sub>	Junction-to-top characterization parameter	1.6	°C/W
Ψ <sub>JB</sub>	Junction-to-board characterization parameter	28.6	°C/W
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	3.2	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

## 6.5 Electrical Characteristics: Main Amplifier

 $V_{S+} = 5 V$ ,  $V_{S-} = 0 V$ ,  $V_{OCM} = 2.5 V$ ,  $V_{ICM} = 2.5 V$ ,  $V_{G-} = 0 V$ ,  $V_{G+} = 1 V$  (maximum gain),  $T_A = 25^{\circ}C$ , AC performance measured using the AC test circuit shown in Figure 16 (unless otherwise noted). DC performance is measured using the DC test circuit shown in Figure 17 (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
AC PERFORMANCE					
Small-signal bandwidth	All gains, $P_{IN} = -45 \text{ dBm}$		300		MHz
Slew rate <sup>(1)</sup>	1-V <sub>PP</sub> Step, 25% to 75%, minimum gain		1250		V/µs
Settling time to 1% <sup>(1)</sup>	1-V <sub>PP</sub> Step, minimum gain		11		ns
Harmonic distortion, 2nd harmonic	f = 32 MHz, $V_{O(PP)}$ = 1 V, $R_{L(diff)}$ = 400 $\Omega$		-65		dBc
Harmonic distortion, 3rd harmonic	f = 32 MHz, $V_{O(PP)}$ = 1 V, $R_{L(diff)}$ = 400 $\Omega$		-61		dBc
Third-order intermodulation distortion	$P_O = -10$ dBm each tone, f <sub>C</sub> = 70 MHz, 200-kHz tone spacing		-62		dBc
Third-order output intercept point	f <sub>C</sub> = 70 MHz, 200-kHz tone spacing		21		dBm
Noise figure (with input termination)	Source impedance: 50 Ω		9		dB
Total input voltage noise	f > 100 kHz		1.1		nV/√Hz
DC PERFORMANCE—INPUTS					
	$T_A = 25^{\circ}C$		20	39	
nput bias current	$T_{A} = -40^{\circ}C$ to +125°C			40	μA
nput bias current offset			<150		pА
	Minimum gain, T <sub>A</sub> = 25°C		1.5	1.6	
Minimum input voltage	Minimum gain, $T_A = -40^{\circ}C$ to $+125^{\circ}C$			1.7	V
	Minimum gain, $T_A = 25^{\circ}C$	3.2	3.3		
Maximum input voltage	Minimum gain, $T_A = -40^{\circ}C$ to $+125^{\circ}C$	3.15			V
	$T_A = 25^{\circ}C$	56	114		
Common-mode rejection ratio	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$	44			dB
Differential input impedance			8.5    3		kΩ    pF
DC PERFORMANCE—OUTPUTS					
	All gains, $T_A = 25^{\circ}C$		±100	±410	
Output offset voltage	All gains, $T_A = -40^{\circ}$ C to +125°C		2.00	±480	mV
	$T_{A} = 25^{\circ}C$	3.25	3.5		
Maximum output voltage high	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$	3	0.0		
	$T_{A} = 25^{\circ}C$	Ŭ	1.5	1.8	
Minimum output voltage low	$T_{A} = -40^{\circ}$ C to +125°C			2	V
	$T_{A} = 25^{\circ}C$	±16	±30	2	
Dutput current	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$	±16	200		mA
Output impedance	T <sub>A</sub> = 40 0 10 1120 0	10	15		Ω
OUTPUT COMMON-MODE VOLTAGE C	ONTROL		10		12
Small-signal bandwidth			32		MHz
Gain			1		V/V
Jaili	$T_A = 25^{\circ}C$		4.5	12	V/ V
Common-mode offset voltage			4.5		mV
	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		4 75	13.8	V
Minimum input voltage			1.75		V
Maximum input voltage			3.25		
nput impedance			25    1		kΩ    pF
Default voltage, with no connect			2.5		V
nput bias current			<1		μA
			0		
Gain control differential voltage range	V <sub>G+</sub>		0 to 1		V
Minus gain control voltage	V <sub>G</sub> V <sub>S</sub> _	-	-0.6 to 0.8		V
Minimum gain	$V_{G+} = 0 V$		11.6		dB
Maximum gain	$V_{G+} = 0.9 V$		46.5		dB
Gain slope	$V_{G+} = 0 V \text{ to } 0.9 V$		38.8		dB/V

(1) Slew rate and settling time measured at amplifier output.

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# **Electrical Characteristics: Main Amplifier (continued)**

 $V_{S+} = 5 V$ ,  $V_{S-} = 0 V$ ,  $V_{OCM} = 2.5 V$ ,  $V_{ICM} = 2.5 V$ ,  $V_{G-} = 0 V$ ,  $V_{G+} = 1 V$  (maximum gain),  $T_A = 25^{\circ}C$ , AC performance measured using the AC test circuit shown in Figure 16 (unless otherwise noted). DC performance is measured using the DC test circuit shown in Figure 17 (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
Gain slope variation	V <sub>G+</sub> = 0 V to 0.9 V		±1.5		dB/V	
	V <sub>G+</sub> = 0 V to 0.15 V		±4			
Gain error	V <sub>G+</sub> = 0.15 V to 0.9 V		±2.25		dB	
Gain control input bias current			<1		μA	
Gain control input resistance			40		kΩ	
Gain control bandwidth	Small signal –3 dB		15		MHz	
VOLTAGE CLAMPING				1		
Output voltages (V <sub>OUT±</sub> ) relative to clamp	Device In voltage limiting mode, $T_A = 25^{\circ}C$		±25	±40		
voltages (V <sub>CL±</sub> )	Device In voltage limiting mode, $T_A = -40^{\circ}C$ to $+125^{\circ}C$			±180	mV	
Clamp voltage (V <sub>CL±</sub> ) input resistance	Device in voltage limiting mode		3.3		kΩ	
Clamp voltage (V <sub>CL±</sub> ) limits		١	/ <sub>S-</sub> to V <sub>S+</sub>		V	
POWER SUPPLY				1		
	T <sub>A</sub> = 25°C		5	5.5	.,	
Specified operating voltage	$T_{A} = -40^{\circ}C \text{ to } +125^{\circ}C$			5.5	V	
	T <sub>A</sub> = 25°C		40	48		
Maximum quiescent current	$T_{A} = -40^{\circ}C \text{ to } +125^{\circ}C$			49	mA	
	T <sub>A</sub> = 25°C	70	77			
Power supply rejection (±PSRR)	$T_{A} = -40^{\circ}C \text{ to } +125^{\circ}C$	45			dB	
POWER DOWN	+ +			+		
	TTL low = shut down, $T_A = 25^{\circ}C$		1.4			
Enable voltage threshold	TTL low = shut down, $T_A = -40^{\circ}$ C to +125°C	1			V	
	TTL high = normal operation, $T_A = 25^{\circ}C$		1.4			
Disable voltage threshold	TTL high = normal operation, $T_A = -40^{\circ}$ C to +125°C			1.65	V	
	T <sub>A</sub> = 25°C		0.35	0.4		
Power-down quiescent current	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$			0.55	mA	
	T <sub>A</sub> = 25°C		±9	±16		
nput current high	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$			±19	μA	
	T <sub>A</sub> = 25°C		±109	±116		
nput current low	$T_{A} = -40^{\circ}C \text{ to } +125^{\circ}C$			±130	μA	
nput impedance			50    1		kΩ    pł	
Turnon time delay	Measured to 50% quiescent current		820		ns	
Turnoff time delay	Measured to 50% quiescent current		500		ns	
Forward isolation in power down			80		dB	
nput resistance in power down			> 1		MΩ	
Output resistance in power down			16		kΩ	

# 6.6 Package Thermal Data

PACKAGE	PCB	T <sub>A</sub> = 25°C POWER RATING <sup>(1)</sup>
PWP (14-pin) <sup>(2)</sup>	See Layout.	3 W

(1) This data was taken using 2 oz trace and copper pad that is soldered directly to a 3 in x 3 in PCB.

(2) The THS7530-Q1 incorporates a PowerPAD on the underside of the chip. The PowerpAD acts as a heatsink and must be connected to a thermally dissipative plane for proper power dissipation. Failure to do so may result in exceeding the maximum junction temperature which could permanently damage the device. See TI technical briefs SLMA002 and SLMA004 for more information about using the PowerPAD thermally enhanced package.



### 6.7 Typical Characteristics

Measured using the AC test circuit shown in Figure 16 (unless otherwise noted).

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		FIGURE
Voltage Gain to Load	vs Frequency (Input at 45 dBm)	Figure 1
Gain and Gain Error	vs V <sub>G+</sub>	Figure 2
Noise Figure	vs Frequency	Figure 3
Output Intercept Point	vs Frequency	Figure 4
1-dB Compression Point	vs Frequency	Figure 5
Total Input Voltage Noise	vs Frequency	Figure 6
Intermodulation Distortion	vs Frequency	Figure 7
Harmonic Distortion	vs Frequency	Figure 8
S-Parameters	vs Frequency	Figure 24
Differential Input Impedance of Main Amplifier	vs Frequency	Figure 25
Differential Output Impedance of Main Amplifier	vs Frequency	Figure 9
V <sub>G+</sub> Input Impedance	vs Frequency	Figure 10
V <sub>OCM</sub> Input Impedance	vs Frequency	Figure 11
Common-Mode Rejection Ratio	vs Frequency	Figure 12
Step Response: 2 V <sub>PP</sub>	vs Time	Figure 13
Step Response: Rising Edge	vs Time	Figure 14
Step Response: Falling Edge	vs Time	Figure 15





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# 7 Parameter Measurement Information

7.1 Test Circuits



Figure 16. AC Test Circuit



Figure 17. DC Test Circuit



# 8 Detailed Description

### 8.1 Overview

The THS7530-Q1 device is a fully-differential amplifier with 300-MHz bandwidth and with continually-variable gain from 11.6 dB to 46.5 dB. This amplifier together with an automatic gain control (AGC) circuit will precisely established a desired amplitude at its output.

The input architecture is a modified Gilbert cell. The output from the Gilbert cell is converted to a voltage and buffered to the output as a fully-differential signal. A summing node between the outputs is used to compare the output common-mode voltage to the  $V_{OCM}$  input. The  $V_{OCM}$  error amplifier then servos the output common-mode voltage to the  $V_{OCM}$  input. Left unterminated,  $V_{OCM}$  is set to midsupply by internal resistors.

The gain control input is conditioned to give linear-in-dB gain control (block H). The gain control input is a differential signal from 0 V to 0.9 V which varies the gain from 11.6 dB to 46.5 dB.

 $V_{CL+}$  and  $V_{CL-}$  provide inputs that limit the output voltage swing of the amplifier.

#### 8.2 Functional Block Diagram



#### 8.3 Feature Description

The main features of the THS7530-Q1 device are continually-variable gain control, common-mode voltage control, output voltage clamps, and power-down mode.

#### 8.3.1 Continually-Variable Gain Control

The amplifier gain in dB is a linear function of the gain control voltage, which has a range of 0 V to 0.9 V. The slope of the gain control input is 38.8 dB/V with a gain range of 11.6 dB to 46.5 dB, which is 3.8 to 211.3 V/V, respectively. The bandwidth of the gain control is 15 MHz, typically.

The gain control is a differential input to reduce noise due to ground bounce, coupling, and so forth. The negative gain-control input  $V_{G-}$  can be below the negative supply by as much as 600 mV.

#### 8.3.2 Common-Mode Voltage Control

The common-mode voltage control sets the common-mode voltage of the differential output. The gain of the control voltage is 1 V/V with a range of 1.75 V to 3.25 V above the negative supply. If unconnected, the common-mode voltage control is at mid-supply, typically 2.5 V above the negative supply. The bandwidth of the common-mode voltage control is an impressive 32 MHz.

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#### **Feature Description (continued)**

#### 8.3.3 Output Voltage Clamps

Separate inputs,  $V_{CL-}$  and  $V_{CL+}$ , establish the minimum and maximum output voltages, respectively. The typical error of the output voltage compared to the clamp voltage is only 25 mV. This feature can be used to avoid saturating the inputs of a receiving device, thereby precluding long recovery times in the signal path.

#### 8.3.4 Power-Down Mode

To minimize power consumption when idle, the THS7530-Q1 device has an active-low power-down control that reduces the quiescent current from 40 mA to 350 µA. The turnon delay is only 820 ns.

When in power-down mode, the THS7530-Q1 device has a 80-dB forward isolation to allow other devices to drive the same signal path with minimal interference from the idle THS7530-Q1 device.

#### 8.4 Device Functional Modes

The THS7530-Q1 device has two functional modes: full-power mode and power-down mode. The power-down mode reduces the quiescent current of the device to 350 µA from a typical value of 40 mA.

With a turnon time of only 820 ns and a turnoff time of 500 ns, the power-down mode can be used to greatly reduce the average power consumption of the device without sacrificing system performance.



# 9 Application and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 9.1 Application Information

The THS7530-Q1 device is designed to work in a wide variety of applications requiring continuously variable gain and a fully-differential signal path. The common-mode voltage control and the output voltage clamps enable the THS7530-Q1 device to drive a diverse array of receiving circuits.



Figure 18. EVM Schematic: Designed for Use With Typical 50-Ω RF Test Equipment



Figure 19. AC-Coupled Single-Ended Input With AC-Coupled Differential Output

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# **Application Information (continued)**



Figure 20. AC-Coupled Differential Input With AC-Coupled Differential Output



Figure 21. DC-Coupled Single-Ended Input With DC-Coupled Differential Output







## 9.2 Typical Application



Figure 23. Typical Application Circuit

#### 9.2.1 Design Requirements

A typical application circuit is shown in *Figure 23*. Two noteworthy aspects of this circuit are the customer's automatic gain control (AGC) circuit and the THS7530-Q1 input bias circuit.

The proper design of the AGC circuit is essential for the THS7530-Q1 device to operate properly in the customer's application. The method of detecting the amplitude of the differential output of the THS7530-Q1 device and creating the gain-control voltage,  $V_{G+}$ , from the detected amplitude and the reference amplitude,  $V_{ref}$ , are application-specific and beyond the scope of this document. The bandwidth of the amplitude of the THS7530-Q1 amplitude control is 15 MHz, which allows for rapid corrections of amplitude errors but which also allows noise from DC to 15 MHz to create an amplitude error. The trade-off between rapid amplitude correction and amplitude modulation due to noise is an important design consideration.

The input bias currents of the differential inputs of the THS7530-Q1 device are typically 20  $\mu$ A. When the differential inputs are AC-coupled, the bias currents must be supplied as shown in *Figure 23*. In this circuit, the DC bias voltage is mid-supply and the AC differential input impedance is 50  $\Omega$ . The 0.1- $\mu$ F capacitor between the two 24.9- $\Omega$  resistors creates an AC ground for the driving circuit.

#### 9.2.2 Detailed Design Procedure

The THS7530-Q1 device is designed for nominal 5-V power supply from  $V_{S+}$  to  $V_{S-}$ .

The amplifier has fully differential inputs,  $V_{IN+}$  and  $V_{IN-}$ , and fully differential outputs,  $V_{OUT+}$  and  $V_{OUT-}$ . The inputs are high impedance and outputs are low impedance. External resistors are recommended for impedance matching and termination purposes.

The inputs and outputs can be DC-coupled, but for best performance, the input and output common-mode voltage should be maintained at the midpoint between the two supply pins. The output common-mode voltage is controlled by the voltage applied to V<sub>OCM</sub>. Left unterminated, V<sub>OCM</sub> is set to midsupply by internal resistors. A 0.1- $\mu$ F bypass capacitor should be placed between V<sub>OCM</sub> and ground to reduce common-mode noise. The input common-mode voltage defaults to midrail when left unconnected. For voltages other than midrail, V<sub>OCM</sub>must be biased by external means. V<sub>IN+</sub> and V<sub>IN-</sub> both require a nominal 30- $\mu$ A bias current for proper operation. Therefore, ensure equal input impedance at each input to avoid generating an offset voltage that varies with gain.

Voltage applied from V<sub>G</sub> to V<sub>G</sub> to V<sub>G</sub> controls the gain of the part with 38.8-dB/V gain slope. The input can be differential or single ended. V<sub>G</sub> must be maintained within -0.6 V and 0.8 V of V<sub>S</sub> for proper operation. The negative gain input should typically be tied directly to the negative power supply.

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#### **Typical Application (continued)**

 $V_{CL+}$  and  $V_{CL-}$  are inputs that limit the output voltage swing of the amplifier. The voltages applied set an absolute limit on the voltages at the output. Input voltages at  $V_{CL+}$  and  $V_{CL-}$  clamp the output, ensuring that neither output exceeds those values.

The power-down input is a TTL compatible input, referenced to the negative supply voltage. A logic low puts the THS7530-Q1 device in power-saving mode. In power-down mode the part consumes less than 1-mA current, the output goes high impedance, and a high amount of isolation is maintained between the input and output.

Power-supply bypass capacitors are required for proper operation. A 6.8- $\mu$ F tantalum bulk capacitor is recommended if the amplifier is located far from the power supply and may be shared among other devices. A ceramic 0.1- $\mu$ F capacitor is recommended within 0.1-in of the device power pin. The ceramic capacitors should be located on the same layer as the amplifier to eliminate the use of vias between the capacitors and the power pin.

ITEM NO.	DESCRIPTION	SIZE	REFERENCE DESIGNATOR	QTY	PART NUMBER
1	Bead, ferrite, 3 A, 80 Ω	1206	FB1	1	(Steward) HI1206N800R-00
2	Capacitor, tantalum, 6.8 mF, 35 V, 10%	D	C2	1	(AVX) TAJD685K035R
3	Capacitor, ceramic, 0.1 mF, X7R, 16V	508	C1	1	(AVX) 0508YC104KAT2A
5	Capacitor, ceramic, 0.1 mF, X7R, 50 V	805	C3, C7, C12, C13, C14, C15, C16, C17	8	(AVX) 08055C104KAT2A
6	Diode, Schottky, 20 V, 0.5 A	SOD-123	D1	1	(Diodes Inc.) B0520LW-7
7	Resistor, 10 Ω, 1/8 W, 1%	805	R24, R25, R26	3	(PHYCOMP) 9C08052A10R0FKHFT
8	Resistor, 24.9 Ω, 1/8 W, 1%	805	R9, R15	2	(PHYCOMP) 9C08052A24R9FKHFT
9	Resistor, 1 kΩ, 1.8W, 1%	805	R7, R12	2	(PHYCOMP) 9C08052A1001FKHFT
10	Resistor, 3.92 kΩ , 1/8 W, 1%	805	R1	1	(PHYCOMP) 9C08052A3921FKHFT
11	Resistor, 0 Ω, 1/4 W	1206	C4, C5	2	(PHYCOMP) 9C12063A0R00JLHFT
12	Resistor, 49.9 Ω, 1/4 W, 1%	1206	R4	1	(PHYCOMP) 9C12063A49R9FKRFT
13	Pot., ceramic, 1/4 inch square, 1 k $\Omega$		R2	1	(Bourns) 3362P-1-102
14	Pot., ceramic, 1/4 inch square, 10 k $\Omega$		R21, R22, R23	3	(Bourns) 3362P-1-103
15	IC, TLV2371	SOT-23	U2, U3, U4	3	(TI) TLV2371IDBVT
16	Transformer, 1:1	CD542	T1, T2	2	(Mini-Circuits) ADT1-1WT
17	Connector, edge, SMA PCB Jack		J3, J4	2	(Johnson) 142–0701–801
18	Jack, banana receptacle, 0.25-in diameter hole		J1, J2	2	(HH Smith) 101
19	Header, 0.1-in Ctrs, 0.025-in square pins	2 POS.	JP1	1	(Sullins) PZC36SAAN
20	Shunts		JP1	1	(Sullins) SSC02SYAN
21	Test point, black		TP2, TP3, TP4	3	(Keystone) 5001
22	Test points, red		TP1, TP8, TP9, TP10	4	(Keystone) 5000
23	Standoff, 4-40 Hex, 0.625-in Length			4	(Keystone) 1804
24	Screw, Phillips, 4–40, .250-in			4	SHR-0440-016-SN
25	IC, THS7530-Q1		U1	1	(TI) THS7530QPWPRQ1
26	Board, printed circuit			1	(TI) EDGE # 6441987

#### Table 2. THS7530EVM Bill of Materials



#### 9.2.3 Application Curves

Figure 24 and Figure 25 highlight the input characteristics of the THS7530-Q1 device that should be used to design the circuit driving the THS7530-Q1 device.



# **10** Power Supply Recommendations

The THS7530-Q1 device is principally intended to operate with a nominal single-supply voltage of 5 V. Supply voltage tolerances of ±10% are supported. The absolute maximum supply is 5.5 V.

Supply decoupling is required, as described in *Application and Implementation*.

Split (or bipolar) supplies can be used with the THS7530-Q1 device, as long as the total value across the device remains less than 5.5 V (absolute maximum).

THS7530-Q1

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#### TEXAS INSTRUMENTS

# 11 Layout

### 11.1 Layout Guidelines

The THS7530-Q1 device is available in a thermally-enhanced PowerPAD<sup>™</sup> package. Figure 26 shows the recommended number of vias and thermal land size recommended for best performance. Thermal vias connect the thermal land to internal or external copper planes and should have a drill diameter sufficiently small so that the via hole is effectively plugged when the barrel of the via is plated with copper. This plug is needed to prevent wicking the solder away from the interface between the package body and the thermal land on the surface of the board during solder reflow. The experiments conducted jointly with Solectron Texas indicate that a via drill diameter of 0.33 mm (13 mils, or .013 in) or smaller works well when 1-ounce copper is plated at the surface of the board and simultaneously plating the barrel of the via. If the thermal vias are not plugged when the copper plating is performed, then a solder mask material should be used to cap the vias with a dimension equal to the via diameter + 0.1 mm minimum. This prevents the solder from being wicked through the thermal via and potentially creating a solder void in the region between the package bottom and the thermal land on the surface of the PCB.



### Figure 26. Recommended Thermal Land Size and Thermal Via Patterns (Dimensions in mm)

See TI's Technical Brief titled, *PowerPAD™ Thermally Enhanced Package* (SLMA002) for a detailed discussion of the PowerPAD™ package, its dimensions, and recommended use.



# Layout Guidelines (continued)





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#### 11.2 Layout Examples



Figure 28. Layout Diagram (Top)



Figure 29. Layout Diagram (Ground)



# Layout Examples (continued)



Figure 30. Layout Diagram (Power)



Figure 31. Layout Diagram (Bottom)

TEXAS INSTRUMENTS

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# **12** Device and Documentation Support

#### 12.1 Device Support

#### 12.1.1 Third-Party Products Disclaimer

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#### 12.1.2 Development Support

For the THS7530 PSpice Model, see SLOJ139.

For the THS7530 TINA-TI Spice Model, see SLAM020.

For the THS7530 TINA-TI Reference Design, see SLAC091.

#### **12.2 Documentation Support**

#### 12.2.1 Related Documentation

For related documentation, see the following:

- THS7530 EVM Users Guide, SLOU161
- Noise Analysis for High-Speed Op Amps, SBOA066
- TI's Analog Signal Chain Guide, SLYB174
- PowerPAD<sup>™</sup> Thermally Enhanced Package, SLMA002
- PowerPAD<sup>™</sup> Made Easy, SLMA004

#### 12.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E<sup>™</sup> Online Community *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support TI's Design Support** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 12.4 Trademarks

PowerPAD, E2E are trademarks of Texas Instruments. All other trademarks are the property of their respective owners.

#### 12.5 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

## 12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



10-Dec-2020

# PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	e Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
THS7530QPWPRQ1	ACTIVE	HTSSOP	PWP	14	3000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 125	T7530Q1	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(<sup>6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF THS7530-Q1 :



# PACKAGE OPTION ADDENDUM

10-Dec-2020

• Catalog: THS7530

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

# PACKAGE MATERIALS INFORMATION

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Texas Instruments

# TAPE AND REEL INFORMATION





# QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All	dimensions	are	nominal	

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THS7530QPWPRQ1	HTSSOP	PWP	14	3000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

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# PACKAGE MATERIALS INFORMATION

26-Feb-2019



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THS7530QPWPRQ1	HTSSOP	PWP	14	3000	350.0	350.0	43.0

# **PWP 14**

# **GENERIC PACKAGE VIEW**

# PowerPAD TSSOP - 1.2 mm max height

4.4 x 5.0, 0.65 mm pitch

PLASTIC SMALL OUTLINE

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





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